Claims

Pursuant to 35 U.S.C. § 121(c), Applicants present the following claim listing:

Claim Listing

Claims 1-10 canceled.

11. (Presently Amended) ~~The method of claim 10, further comprising:~~

A method of analyzing scan tests of an IC device, comprising:

processing data of a device definition, a test program definition, and test execution results to produce cross-reference data interrelating signals, scan chains, test execution results and steps of the test program;

rendering views for presentation on a display, the views including at least a cyclized test view, a procedural test program view, and views of a signal vector, scan state, and scan vector;

selectively presenting the views on the display;

navigating responsive to a user navigation input from a location selected in a current view to a correlated location in a user directed other of the views based on the cross-reference data;

modifying the test program definition in response to user editing inputs;

re-executing the modified test program;

acquiring test execution results from execution of the modified test program; and

repeating the above-recited processing, rendering, presenting and navigating steps ~~recited in claim 10~~ based on the modified test program for analyzing the modified test of the IC device.

12. (New)   A scan test viewing and analysis tool, comprising:

means for processing data of a device definition, a test program definition, and test execution results to produce cross-reference data interrelating signals, scan chains, test execution results and steps of the test program;

means for rendering views for presentation on a display, the views including at least a cyclized test view, a procedural test program view, and views of a signal vector, scan state, and scan vector;

means for selectively presenting the views on the display;

means for navigating responsive to a user navigation input from a location selected in a current view to a correlated location in a user directed other of the views based on the cross-reference data;

means for modifying the test program definition in response to user editing inputs;

means for re-executing the modified test program;

means for acquiring test execution results from execution of the modified test program; and

means for causing the above-recited means for processing, rendering, presenting and navigating to repeat their operations based on the modified test program for analyzing the modified test of the IC device.

13. (New)   A computer-readable program carrying medium having software programming of a scan test tool for an IC tester stored thereon and executable on a computer processor to perform a method comprising:

processing data of a device definition, a test program definition, and test execution results to produce cross-reference data interrelating signals, scan chains, test execution results and steps of the test program;

rendering views for presentation on a display, the views including at least a cyclized test view, a procedural test program view, and views of a signal vector, scan state, and scan vector;

selectively presenting the views on the display;

navigating responsive to a user navigation input from a location selected in a current view to a correlated location in a user directed other of the views based on the cross-reference data;

modifying the test program definition in response to user editing inputs;

re-executing the modified test program;

acquiring test execution results from execution of the modified test program; and

repeating the above-recited processing, rendering, presenting and navigating steps based on the modified test program for analyzing the modified test of the IC device.